ALPHA & OMEGA SEMICONDUCTOR

AO4813
Dual P-Channel Enhancement Mode Field Effect Transistor

General Description

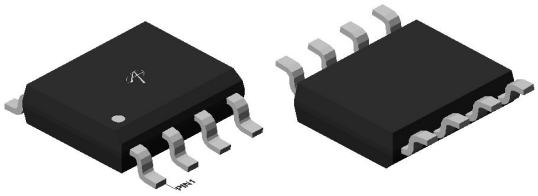
The AO4813/L uses advanced trench technology to provide excellent $R_{DS(ON)}$, and low gate charge. This device is suitable for use as a load switch or in PWM applications.
AO4813 and AO4813L are electrically identical.
-RoHS Compliant
-AO4813L is Halogen Free

Features

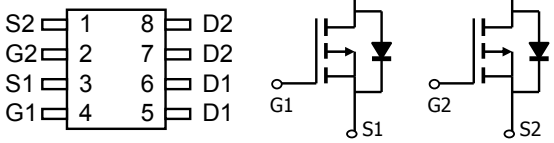
V_{DS} (V) = -30V
I_D = -7.1 A (V_{GS} = -10V)
$R_{DS(ON)}$ < 25mΩ (V_{GS} = -10V)
$R_{DS(ON)}$ < 40mΩ (V_{GS} = -4.5V)

100% UIS Tested!

SOIC-8



SOIC-8
Top View



Absolute Maximum Ratings T_A=25°C unless otherwise noted

Parameter		Symbol	Maximum	Units
Drain-Source Voltage		V_{DS}	-30	V
Gate-Source Voltage		V_{GS}	±20	V
Continuous Drain Current [AF]	T_A=25°C	I_D	-7.1	A
	T_A=70°C		-5.6	
Pulsed Drain Current [B]		I_{DM}	-30	
Power Dissipation	T_A=25°C	P_D	2	W
	T_A=70°C		1.28	
Avalanche Current [B]		I_{AR}	11	A
Repetitive avalanche energy 0.3mH [B]		E_{AR}	18	mJ
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient [A]	t ≤ 10s	$R_{\theta JA}$	48	62.5	°C/W
Maximum Junction-to-Ambient [A]	Steady-State		74	110	°C/W
Maximum Junction-to-Lead [C]	Steady-State	$R_{\theta JL}$	35	40	°C/W

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	I_D=-250µA, V_{GS}=0V	-30			V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS}=-30V, V_{GS}=0V			-1	µA
		T_J=55°C			-5	
I_{GSS}	Gate-Body leakage current	V_{DS}=0V, V_{GS}=±20V			±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS}=V_{GS} I_D=-250µA	-1.4	-2	-2.7	V
$I_{D(ON)}$	On state drain current	V_{GS}=-10V, V_{DS}=-5V	-30			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V_{GS}=-10V, I_D=-7.1A		20	25	mΩ
		T_J=125°C		27	33	
		V_{GS}=-4.5V, I_D=-5.6A		29	40	mΩ
g_{FS}	Forward Transconductance	V_{DS}=-5V, I_D=-7.1A		19.6		S
V_{SD}	Diode Forward Voltage	I_S=-1A,V_{GS}=0V		-0.7	-1	V
I_S	Maximum Body-Diode Continuous Current				-4.2	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	V_{GS}=0V, V_{DS}=-15V, f=1MHz		1573	1888	pF
C_{oss}	Output Capacitance			319		pF
C_{rss}	Reverse Transfer Capacitance			211	295	pF
R_g	Gate resistance	V_{GS}=0V, V_{DS}=0V, f=1MHz	3	6.7	13	Ω
SWITCHING PARAMETERS						
Q_g(10V)	Total Gate Charge (10V)	V_{GS}=-10V, V_{DS}=-15V, I_D=-7.1A		30.9	40	nC
Q_g(4.5V)	Total Gate Charge (4.5V)			16.1	21	nC
Q_{gs}	Gate Source Charge			8		nC
Q_{gd}	Gate Drain Charge			4.4		nC
$t_{D(on)}$	Turn-On DelayTime	V_{GS}=-10V, V_{DS}=-15V, R_L=2.2Ω, R_{GEN}=3Ω		9.5		ns
t_r	Turn-On Rise Time			8		ns
$t_{D(off)}$	Turn-Off DelayTime			44.2		ns
t_f	Turn-Off Fall Time			22.2		ns
t_{rr}	Body Diode Reverse Recovery Time	I_F=-7.1A, dI/dt=100A/µs		25.5	31	ns
Q_{rr}	Body Diode Reverse Recovery Charge	I_F=-7.1A, dI/dt=100A/µs		14.7		nC

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature.

C. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to lead $R_{\theta JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using <300 µs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The SOA curve provides a single pulse rating.

F. The current rating is based on the t≤ 10s junction to ambient thermal resistance rating.

Rev8: Oct 2008

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: P-CHANNEL

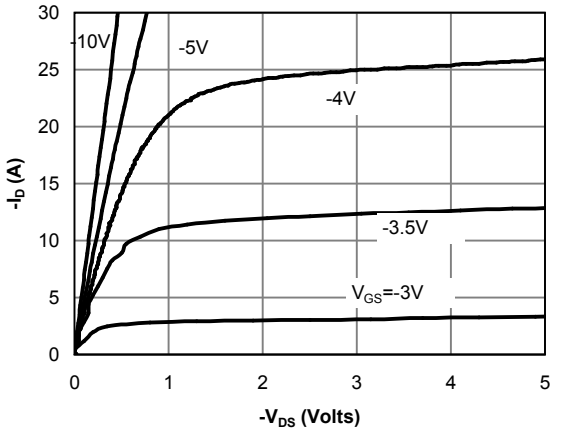


Fig 1: On-Region Characteristics

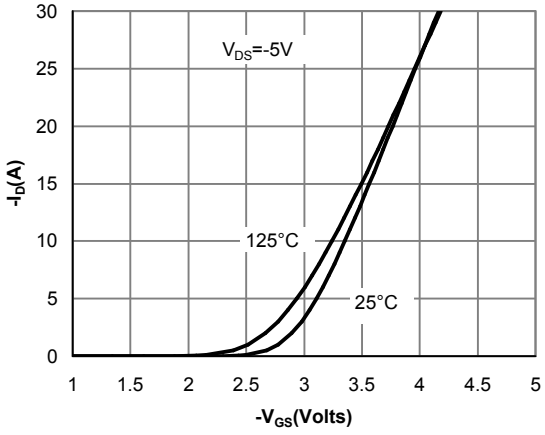


Figure 2: Transfer Characteristics

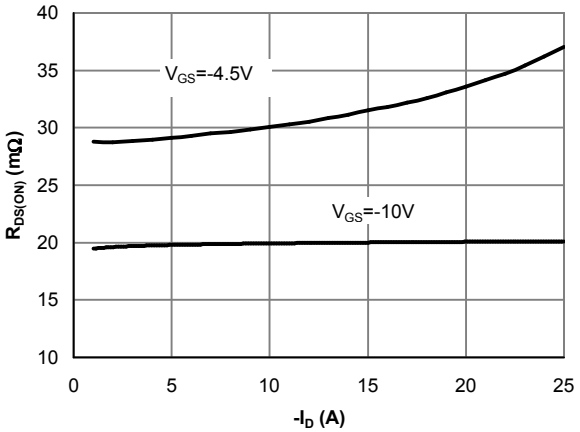


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

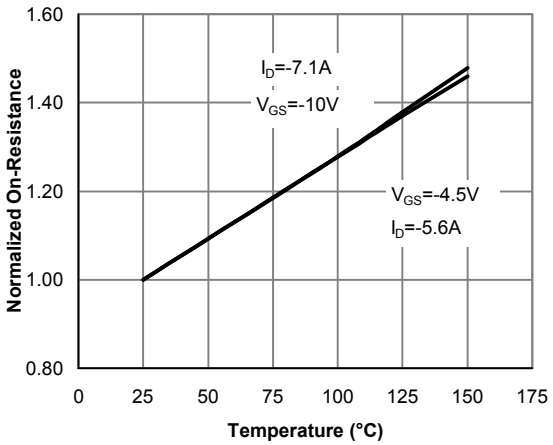


Figure 4: On-Resistance vs. Junction Temperature

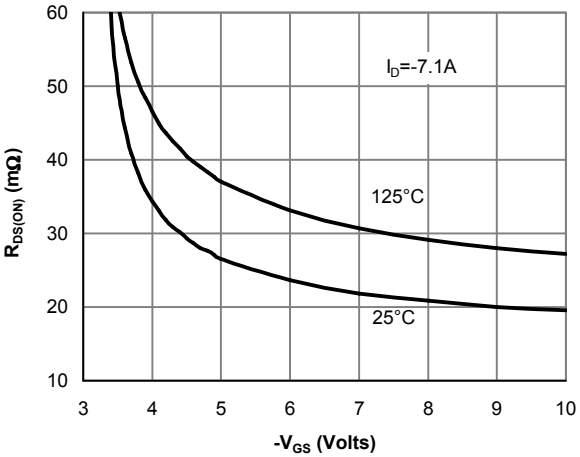


Figure 5: On-Resistance vs. Gate-Source Voltage

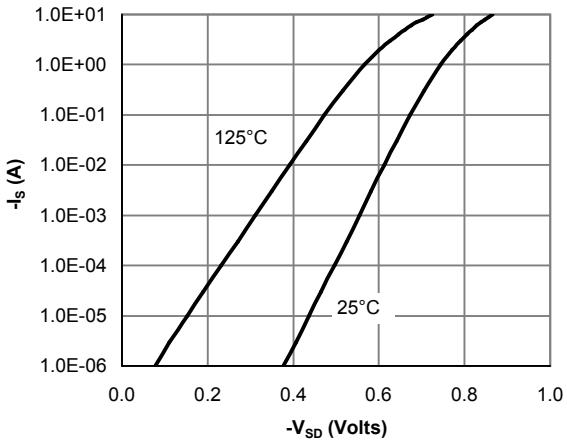


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: P-CHANNEL

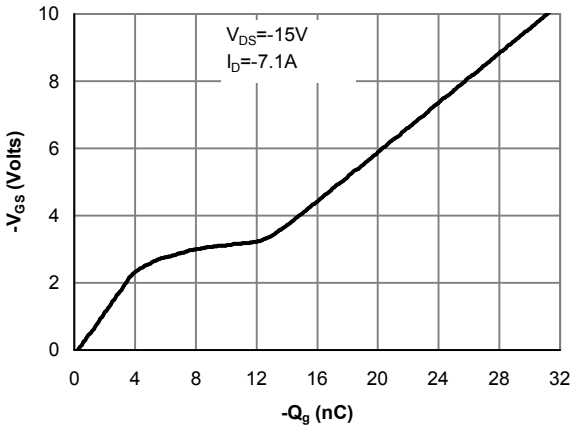


Figure 7: Gate-Charge Characteristics

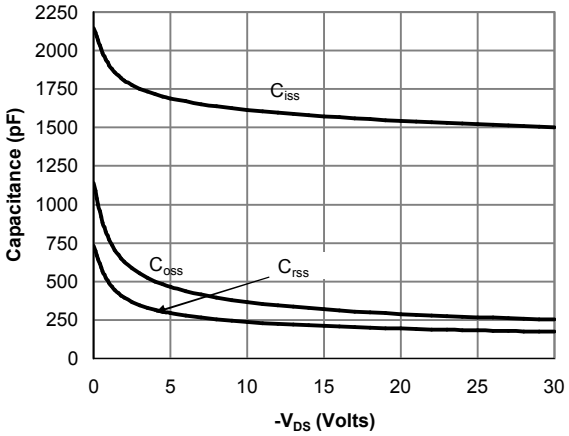


Figure 8: Capacitance Characteristics

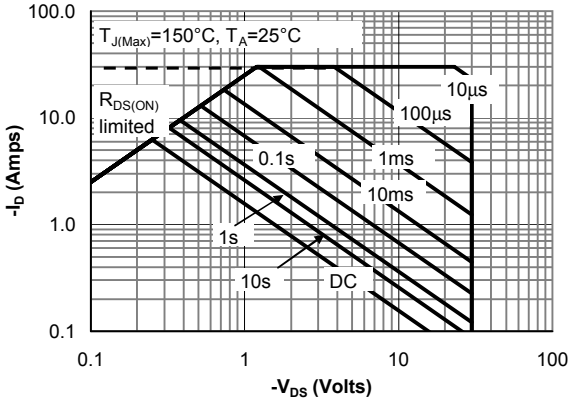


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

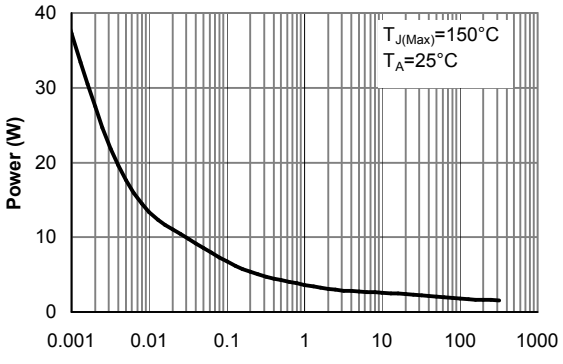


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

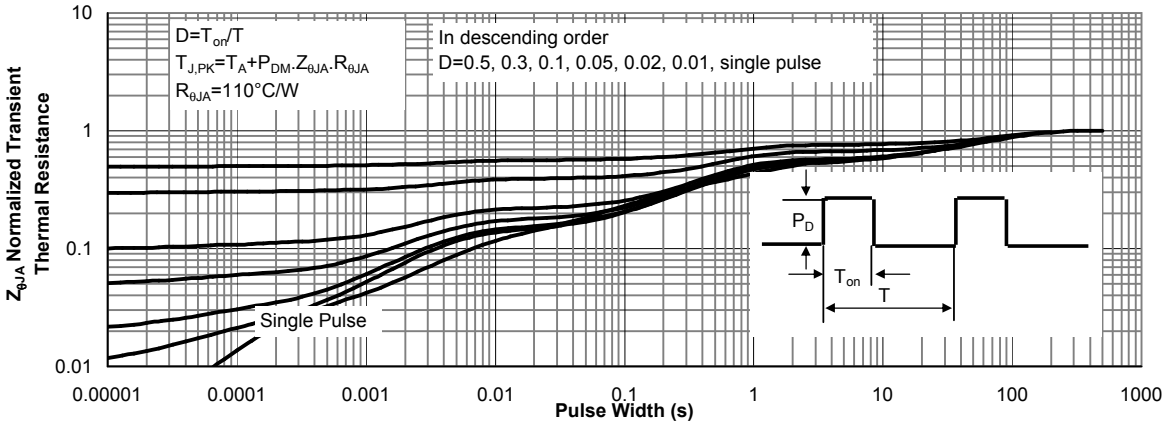
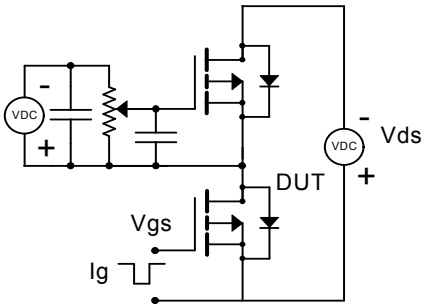
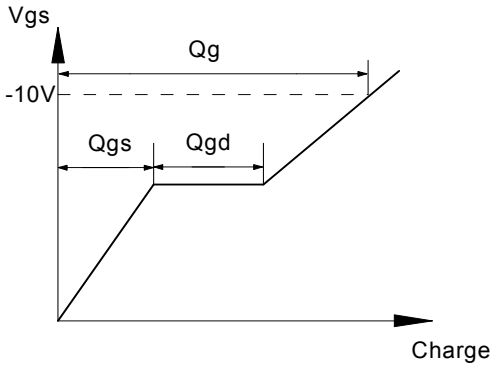


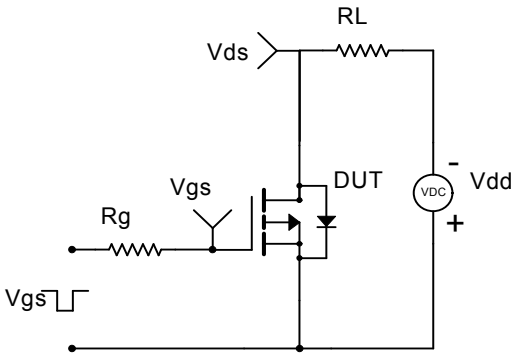
Figure 11: Normalized Maximum Transient Thermal Impedance

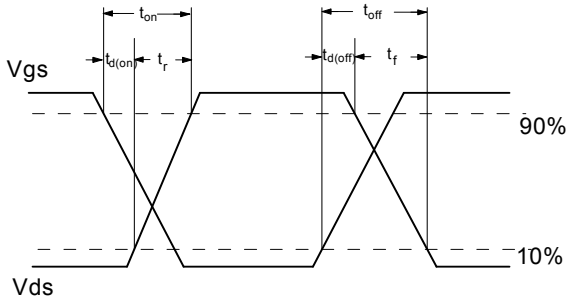
Gate Charge Test Circuit & Waveform



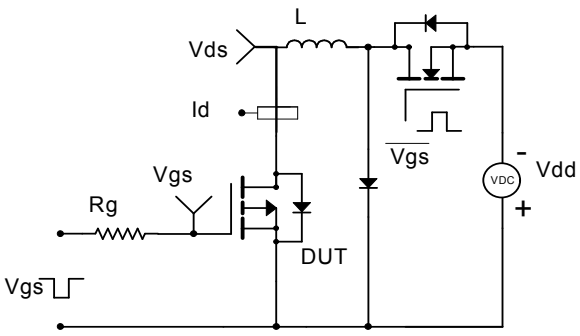


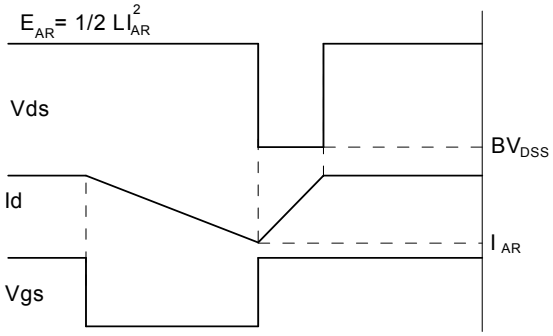
Resistive Switching Test Circuit & Waveforms





Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





Diode Recovery Test Circuit & Waveforms